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L2	424801	edge with direction	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/15 10:22
L3	9653	edge with direction with image	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/15 10:22
L4	1411	((vertical, left,right, horizontal)with edge) with direction with image	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/15 10:23
L5	669	((vertical, left,right, horizontal)near4 edge) with direction with image	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/15 10:23
L6	11	((vertical, left,right, horizontal)near4 edge) with direction with image with coefficient	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/15 10:24
L7	0	((vertical with left with right with horizontal)with edge) with direction with image with coefficient	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/15 10:24
L8	35	((vertical with left with right with horizontal)with edge) with direction with image	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/15 10:24
L9	26	namizuka near2 y	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/15 11:02

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S2	8	382/266.ccls. and (user with coefficient)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 07:40

L10	2	(namizuka near2 y) and coefficient	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/15 11:02
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1 Channel tracking for RAKE receivers in closely spaced multipath environments

Fock, G.; Baltersee, J.; Schulz-Rittich, P.; Meyr, H.

Selected Areas in Communications, IEEE Journal on, Volume: 19, Issue: 12, Dec. 2001
Pages:2420 - 2431

[\[Abstract\]](#) [\[PDF Full-Text \(255 KB\)\]](#) IEEE JNL

2 Rate-scalable object-based wavelet codec with implicit shape coding

Kassim, A.A.; Lifeng Zhao;

Circuits and Systems for Video Technology, IEEE Transactions on, Volume: 10, Issue: 7, Oct. 2000
Pages:1068 - 1079

[\[Abstract\]](#) [\[PDF Full-Text \(808 KB\)\]](#) IEEE JNL

3 Automatic detection of the boundary of the calcaneus from ultrasound parametric images using an active contour model; clinical assessment

Lefebvre, F.; Berger, G.; Laugier, P.

Medical Imaging, IEEE Transactions on, Volume: 17, Issue: 1, Feb. 1998
Pages:45 - 52

[\[Abstract\]](#) [\[PDF Full-Text \(232 KB\)\]](#) IEEE JNL

4 Optimal orientation function for SAW devices

Cowperthwaite, J.A.; da Cunha, M.P.

Frequency Control Symposium and PDA Exhibition Jointly with the 17th European Frequency and Time Forum, 2003. Proceedings of the 2003 IEEE International, 4-8 May 2003
Pages:881 - 887

[\[Abstract\]](#) [\[PDF Full-Text \(530 KB\)\]](#) IEEE CNF

5 Unsupervised contour estimation

Figueiredo, M.A.T.; Leitao, J.M.N.

Image Processing, 1996. Proceedings., International Conference on, Volume: 1, 16-19 Sept. 1996
Pages:821 - 824 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(324 KB\)\]](#) IEEE CNF

6 Electromagnetic modeling of objects with curved edges and surfaces using the conformal FDTD

Lai-Ching Ma; Wenhua Yu; El-Raouf, H.E.

Antennas and Propagation Society International Symposium, 2003. IEEE, Volume: 3, 22-27 June 2003
Pages:103 - 106